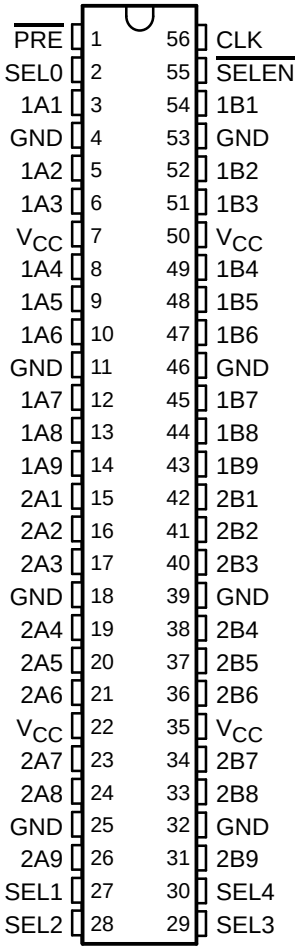
- **Member of the Texas Instruments *Widebus+*™ Family**
- ***EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process**
- ***UBE*™ (Universal Bus Exchanger) Allows Synchronous Data Exchange**
- **Designed to Facilitate Incident-Wave Switching for Line Impedances of 50 Ω or Greater**
- **Typical V_{OLP} (Output Ground Bounce) < 0.8 V at V_{CC} = 3.3 V, T_A = 25°C**
- **Typical V_{OHV} (Output V_{OH} Undershoot) > 2 V at V_{CC} = 3.3 V, T_A = 25°C**
- **ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Bus-Hold On Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors**
- **Latch-Up Performance Exceeds 250 mA Per JEDEC Standard JESD-17**
- **Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages**

DGG OR DL PACKAGE
(TOP VIEW)



description

The SN74ALVC16409 allows synchronous data exchange between four different buses.

Data flow is controlled by the select (SEL0–SEL4) inputs. A data-flow state is stored on the rising edge of the clock (CLK) input, provided the select-enable ($\overline{\text{SELEN}}$) input is low. Once a data-flow state has been established, data is stored in the flip-flop on the rising edge of the CLK, provided $\overline{\text{SELEN}}$ is high.

The data-flow control logic is designed to allow glitch-free data transmission.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVC16409 is available in TI's shrink small-outline (DL) and thin shrink small-outline (DGG) packages, which provide twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

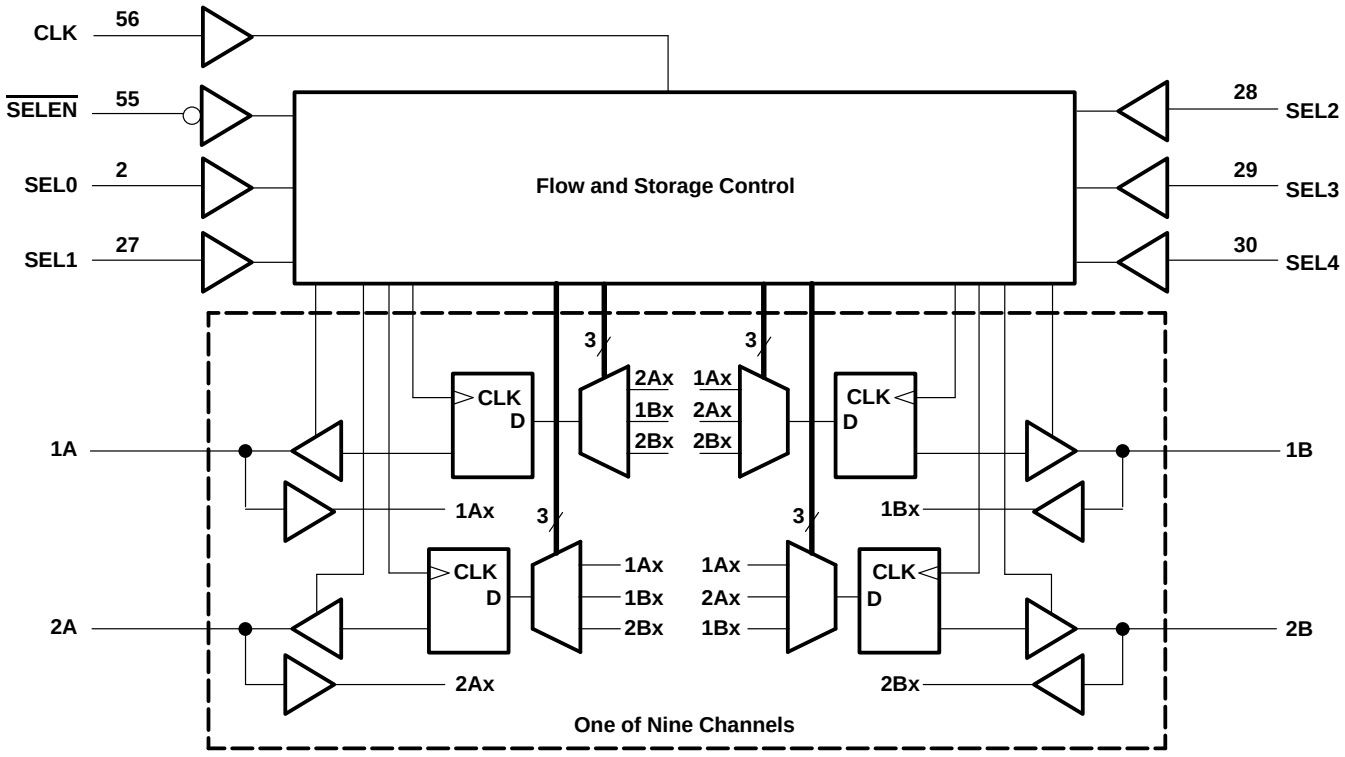
The SN74ALVC16409 is characterized for operation from –40°C to 85°C.

PRODUCT PREVIEW

Widebus+, EPIC, and UBE are trademarks of Texas Instruments Incorporated.

PRODUCT PREVIEW

logic diagram (positive logic)



FUNCTION TABLE

INPUTS		OUTPUT RECEIVE PORT
CLK	SEND PORT	
X	X	B_0†
X	L	L
X	H	H
↑	L	L
↑	H	H
H	X	B_0†
L	X	B_0†

† Output level before the indicated steady-state input conditions were established.

DATA-FLOW CONTROL FUNCTION TABLE

INPUTS							DATA FLOW
$\overline{\text{SELEN}}$	CLK	SEL0	SEL1	SEL2	SEL3	SEL4	
H	↑	X	X	X	X	X	No change
L	↑	0	0	0	0	0	None, all I/Os off
L	↑	0	0	0	0	1	Not used
L	↑	0	0	0	1	0	Not used
L	↑	0	0	0	1	1	Not used
L	↑	0	0	1	0	0	Not used
L	↑	0	0	1	0	1	Not used
L	↑	0	0	1	1	0	Not used
L	↑	0	0	1	1	1	Not used
L	↑	0	1	0	0	0	2A to 1A and 1B to 2B
L	↑	0	1	0	0	1	2A to 1A
L	↑	0	1	0	1	0	2B to 1B
L	↑	0	1	0	1	1	2A to 1A and 2B to 1B
L	↑	0	1	1	0	0	1A to 2A and 1B to 2B
L	↑	0	1	1	0	1	1A to 2A
L	↑	0	1	1	1	0	1B to 2B
L	↑	0	1	1	1	1	1A to 2A and 2B to 1B
L	↑	1	0	0	0	0	1A to 1B and 2B to 2A
L	↑	1	0	0	0	1	1A to 1B
L	↑	1	0	0	1	0	2A to 2B
L	↑	1	0	0	1	1	1A to 1B and 2A to 2B
L	↑	1	0	1	0	0	1B to 1A and 2A to 2B
L	↑	1	0	1	0	1	1B to 1A
L	↑	1	0	1	1	0	2B to 2A
L	↑	1	0	1	1	1	1B to 1A and 2B to 2A
L	↑	1	1	0	0	0	2B to 1A and 2A to 1B
L	↑	1	1	0	0	1	1B to 2A
L	↑	1	1	0	1	0	2B to 1A
L	↑	1	1	0	1	1	2B to 1A and 1B to 2A
L	↑	1	1	1	0	0	1A to 2B and 1B to 2A
L	↑	1	1	1	0	1	1A to 2B
L	↑	1	1	1	1	0	2A to 1B
L	↑	1	1	1	1	1	1A to 2B and 2A to 1B

PRODUCT PREVIEW

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC} . . . . . –0.5 V to 4.6 V
Input voltage range, V_I (except I/O ports) (see Note 1) . . . . . –0.5 V to 4.6 V
Input voltage range, V_I (I/O ports) (see Notes 1 and 2) . . . . . –0.5 V to V_{CC} + 0.5 V
Output voltage range, V_O (see Notes 1 and 2) . . . . . –0.5 V to V_{CC} + 0.5 V
Input clamp current, I_{IK} (V_I < 0) . . . . . –50 mA
Output clamp current, I_{OK} (V_O < 0 or V_O > V_{CC}) . . . . . ±50 mA
Continuous output current, I_O (V_O = 0 to V_{CC}) . . . . . ±50 mA
Continuous current through V_{CC} or GND pins . . . . . ±100 mA
Maximum power dissipation at T_A = 55°C (in still air): DGG package . . . . . 1 W
DL package . . . . . 1.4 W
Storage temperature range . . . . . –65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. This value is limited to 4.6 V maximum.

recommended operating conditions

			MIN	MAX	UNIT
V_{CC}	Supply voltage		2.7	3.6	V
V_{IH}	High-level input voltage	V_{CC} = 2.7 V to 3.6 V	2		V
V_{IL}	Low-level input voltage	V_{CC} = 2.7 V to 3.6 V		0.8	V
V_I	Input voltage		0	V_{CC}	V
V_O	Output voltage		0	V_{CC}	V
I_{OH}	High-level output current	V_{CC} = 2.7 V		–12	mA
		V_{CC} = 3 V		–24‡	
I_{OL}	Low-level output current	V_{CC} = 2.7 V		12	mA
		V_{CC} = 3 V		24‡	
$\Delta t/\Delta v$	Input transition rise or fall rate		0	10	ns/V
T_A	Operating free-air temperature		–40	85	°C

‡ Current duty cycle ≤ 50%, f ≥ 1 kHz

PRODUCT PREVIEW

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		V_{CC}†	MIN	TYP	MAX	UNIT
V_{IK}		I_I = –18 mA		2.7 V			–1.2	V
V_{OH}		I_{OH} = –100 μA		MIN to MAX	V_{CC}–0.2			V
		I_{OH} = –12 mA		2.7 V	2.2			
				3 V	2.4			
		I_{OH} = –24 mA		3 V	2			
V_{OL}		I_{OL} = 100 μA		MIN to MAX			0.2	V
		I_{OL} = 12 mA		2.7 V			0.4	
		I_{OL} = 24 mA		3 V			0.55	
I_I		$V_I = V_{CC}$ or GND		3.6 V			±5	μA
$I_{I(hold)}$	Data pins	V_I = 0.8 V		3 V	75			μA
		V_I = 2 V			–75			
I_{OZ}‡		$V_O = V_{CC}$ or GND		3.6 V			±10	μA
I_{CC}		$V_I = V_{CC}$ or GND,	I_O = 0	3.6 V			40	μA
ΔI_{CC}		V_{CC} = 3 V to 3.6 V, Other inputs at V_{CC} or GND	One input at V_{CC} – 0.6 V,				750	μA
C_i	Control inputs	$V_I = V_{CC}$ or GND		3.3 V				pF
C_{io}	A or B ports	$V_O = V_{CC}$ or GND		3.3 V				pF

† For conditions shown as MIN or MAX, use the appropriate values under recommended operating conditions.
‡ For I/O ports, the parameter I_{OZ} includes the input leakage current.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

			V_{CC} = 3.3 V ± 0.15 V		V_{CC} = 3.3 V ± 0.3 V		V_{CC} = 2.7 V	UNIT
			MIN	MAX	MIN	MAX	MIN	
f_{clock}	Clock frequency		0	75				MHz
t_w	Pulse duration	CLK high or low						ns
t_{su}	Setup time	A or B before CLK↑		0.8				ns
		S before CLK↑		5				
		$\overline{SELEN}$ before CLK↑						
t_h	Hold time	A or B after CLK↑		2				ns
		S after CLK↑		0.5				
		$\overline{SELEN}$ after CLK↑						

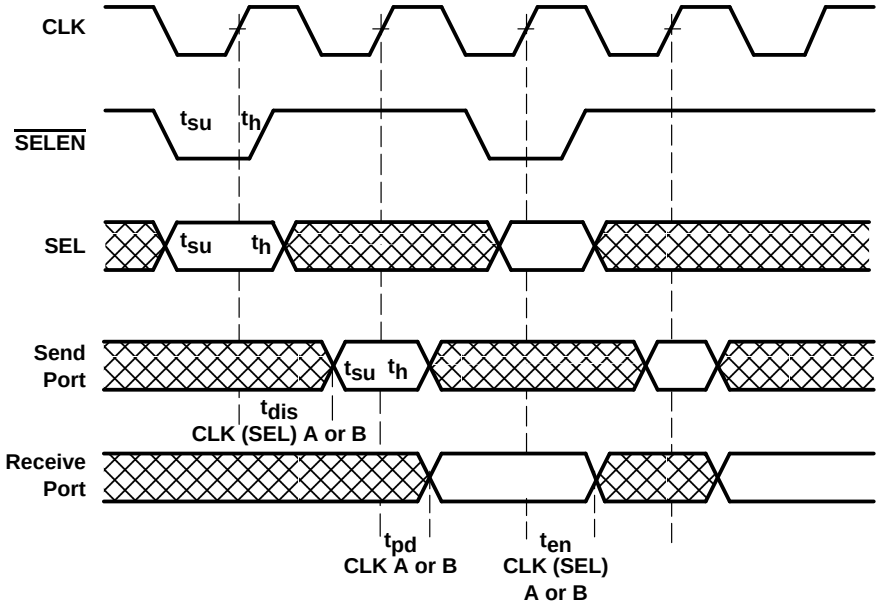
switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 3.3 V ± 0.15 V			V_{CC} = 3.3 V ± 0.3 V			V_{CC} = 2.7 V	UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	MAX	
f_{max}			75							MHz
t_{pd}	CLK (A or B)	B or A			4					ns
t_{en}	CLK (SEL)	B or A								ns
t_{dis}	CLK (SEL)	B or A								ns

NOTE 3: Load circuit and voltage waveforms are shown in Section 1.

PRODUCT PREVIEW

timing diagram



PRODUCT PREVIEW

IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.